

PCN #: 1409
 DATE: 16-May-2014
 PROPOSED SHIP DATE: 16-Aug-2014



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- PROCESS CHANGE NOTICE
 PRODUCT CHANGE NOTICE

MAXIM INTEGRATED HEREBY ISSUES NOTIFICATION OF CHANGE THAT MAY AFFECT THE FOLLOWING CATEGORIES:

| | | | | |
|---------------------------------|------------------------------------|--|-------------------------------|--|
| <input type="checkbox"/> DESIGN | <input type="checkbox"/> WAFER FAB | <input checked="" type="checkbox"/> ASSEMBLY | <input type="checkbox"/> TEST | <input type="checkbox"/> ELEC/MECH SPECS |
|---------------------------------|------------------------------------|--|-------------------------------|--|

AFFECTED PRODUCT:

Ordering P/N: (See PN listing XLS in PCN Zip file) MAX32590

| | |
|---|---------------------------------------|
| CHANGE FROM: Gold bond wire | CHANGE TO: Copper bond wire |
| JUSTIFICATION: We are expanding our capacity at ASE-CL by qualifying the MAX32590 on ASECL's high volume copper bond wire line. See the attached reliability report R25366FQ which qualifies this change to copper wire. | |
| TRACEABILITY: Maxim Integrated maintains full traceability by device marking and the packaging labels or shipment packing slip. | |

Maxim Integrated's Change Notification System is designed to keep our customer base apprised of major product, manufacturing, or facility improvements.

Deborah Meeker / PCN Coordinator

For further information, please contact either of the people listed below.

Contact your local Maxim Integrated or Deborah Meeker, PCN Coordinator
 Company Representative 408-601-5618 / pcn.coordinator@maximintegrated.com

| | | | |
|---------------------|-------------------------------------|----------------------|---------------|
| | TITLE: Notification Only PCN | | |
| Confidential | DOCUMENT I.D. 18-0182 | REVISION F | PAGE 1 |

Qualification
 Evaluation

Report#: R25366FQ_EXT
Date: 11/02/2012

MAXIM RELIABILITY QUALIFICATION REPORT

SUBJECT

ASE ChungLi Taiwan, 376 Pin 0.8 mm Pitch (18x18x1.4mm) and 248 Pin 0.5 mm Pitch (10x10x1.2mm) 0.8 mil Pd coated Cu-Wire Pb-Free CSBGA Package and Assembly Site Qualification.

CONCLUSION

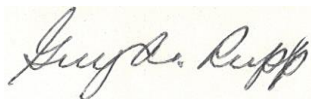
All qualification lots have passed Maxim reliability qualification requirements. In addition, packages have completed Moisture Sensitivity Level 3 testing per JEDEC J-STD-020D.1, and solder reflow test at 260°C peak temperature (Tp). Therefore, assembler ASE ChungLi Taiwan is qualified to build up to 376 Pin 0.8 mm Pitch (18x18x1.4mm) and 248 Pin 0.5mm Pitch (10x10x1.2mm) Pb-Free CSBGA packages with 0.8 mil Pd-coated Cu-Wire.

PACKAGE COVERAGE

Additional CSBGA and CTBGA package families that are also qualified by extension to this qualification at ASE ChungLi Taiwan using same BOM are: all 0.8mm pitch \leq 18x18mm package size, and all 0.5mm pitch \leq 10x10mm package size.

TEST RESULT

See Tables 3, 4, and 5 for details.



Guy Rupp
Senior Principal Member of Technical Staff



Director, Reliability

TEST RESULTS/ LOT INFORMATION:

Table 3.

| TEST | REL#: 25366 (48525) | REL#: 25366 (48526) | REL#: 25366 (48711) | REL#: 25366 (48473) |
|--|---------------------------------|-----------------------|-----------------------|---|
| | DEVICE: MG3500A3 | DEVICE: MG3500A3 | DEVICE: MG3500A3 | DEVICE: MG3500A3 |
| | LOT#: EX105234AE-QUAL | LOT#: EX105234AG-QUAL | LOT#: EX105234AF-QUAL | LOT#: EX105234AD-QUAL (Au-Wire Control Lot) |
| | PKG CODE: X37688+1 | PKG CODE: X37688+1 | PKG CODE: X37688+1 | PKG CODE: X37688+1 |
| | DIE: MG02Z | DIE: MG02Z | DIE: MG02Z | DIE: MG02Z |
| | D/C: 1043 | D/C: 1043 | D/C: 1043 | D/C: 1043 |
| Operating Life | 1000 hours – 0/77 | 0/76 | 0/77 | 0/77 |
| Convection Solder Reflow ^{*1} | 3X – 0/251 | 0/251 | 0/251 | 0/250 |
| Temperature Cycle ^{*2} | 1000 cycles – 0/77 | 0/77 | 0/77 | 0/77 |
| High Temperature Storage ^{*2} | 1000 hours – 0/75 ^{*4} | 0/75 ^{*4} | 0/76 ^{*5} | 0/77 |
| Unbiased HAST ^{*2} | 264 hours – 0/77 | 0/77 | 0/77 | 0/77 |
| Physical Dimensions | 0/10 | 0/10 | 0/10 | 0/10 |
| BGA Ball Shear | 0/24 Balls | 0/24 Balls | 0/24 Balls | 0/24 Balls |
| Wire Bond Pull Strength | 0/40 Wires | 0/40 Wires | 0/40 Wires | 0/40 Wires |
| Wire Bond Ball Shear ^{*3} | 0/24 Wires | 0/24 Wires | 0/24 Wires | 0/24 Wires |
| Bond Crater ^{*2} | 0/18 | 0/20 | 0/20 | 0/19 |

- Note:**
^{*1.} Level 3 soak (30°C/60%R.H. for 192 hrs) is used as preconditioning.
^{*2.} Convection solder reflow at 260°C T_p is used as preconditioning.
^{*3.} Performed by Assembly Site.
^{*4.} Mechanical Damage – 1 unit with solder ball damage not tested at 500 hours.
 1 unit failing DLL experimental test parameter at 500 hours, subsequently eliminated from the test program.
^{*5.} Mechanical Damage – 1 unit with solder ball damage not tested at 500 hours.

Table 4.

| TEST | REL#: 25127 (48531) | REL#: 25127 (48532) | REL#: 25127 (48533, 49122) | REL#: 25127 (48759, 49123) |
|--|--------------------------------|-----------------------|--|--|
| | DEVICE: MAX64180CXO | DEVICE: MAX64180CXO | DEVICE: MAX64180CXO | DEVICE: MAX64180CXO |
| | LOT#: EX114143AA-QUAL | LOT#: EX114143AB-QUAL | LOT#: EX114143AC-QUAL | LOT#: EX114143AD (Au-Wire Control Lot) |
| | PKG CODE: X24800+1 | PKG CODE: X24800+1 | PKG CODE: X24800+1 | PKG CODE: X24800+1 |
| | DIE: MG02Z | DIE: MG02Z | DIE: MG02Z | DIE: MG02Z |
| | D/C: 1049 | D/C: 1049 | D/C: 1049 | D/C: 1049 |
| Convection Solder Reflow ^{*1} | 3X – 0/50 | 0/50 | 0/100 | 0/50 |
| Biased HAST ^{*2} | 264 hours – 0/44 ^{*4} | 0/42 ^{*5} | 1/45 ^{*6} | 0/44 ^{*7} |
| Repeat Biased HAST ^{*2} | – | – | 264 hours – 0/45 | 0/45 |
| Wire Bond Pull Strength (gm-f) Avg, StdDev, Max, Min, C _{pk} | – | – | <u>0/200, 0/200 Wires</u> 6.49, 0.61, 9.55, 5.45, <u>1.89</u> 7.0, 0.9, 9.6, 4.5, <u>1.5</u> | – |
| Wire Bond Ball Shear ^{*3} | 0/24 Wires | 0/24 Wires | 0/24 Wires | 0/24 Wires |
| Bond Crater ^{*2} | – | – | 0/10 | – |

- Note:**
^{*1.} Level 3 soak (30°C/60%R.H. for 192 hrs) is used as preconditioning.
^{*2.} Convection solder reflow at 260°C T_p is used as preconditioning.
^{*3.} Performed by Assembly Site.
^{*4.} 1 unit failed due to EOS damage near ball bond pads 293-295. IFAR40033616, not a valid package failure.
^{*5.} 1 HAST Board removed for socket repairs, leaving 7 HAST Boards with 6 sockets per board = 42 units.
^{*6.} 1 unit failed due to lifted ball bond #292 at bond pad #479. IFAR40035100/SCAR30598 inconclusive.
 Therefore, 3 post-SCAR resubmission lots were required for additional reliability stress testing.
^{*7.} 1 unit failed due to EOS damage in the LVCMOS IO blocks. IFAR40035448, not a valid package failure.

TEST RESULTS/ LOT INFORMATION: continued

Table 5. Post-SCAR# 30598 Qual Lots Summary

| TEST | REL#: 26332 (49318) | REL#: 26332 (49319) | REL#: 26332 (49320) |
|--|---|---|--|
| | DEVICE: MAX64180CXO | DEVICE: MAX64180CXO | DEVICE: MAX64180CXO |
| | LOT#: EX117902AF-QUAL | LOT#: EX117902AG-QUAL | LOT#: EX117902AH-QUAL |
| | PKG CODE: X24800+1 | PKG CODE: X24800+1 | PKG CODE: X24800+1 |
| | DIE: MG02Z | DIE: MG02Z | DIE: MG02Z |
| | D/C: 1147 | D/C: 1147 | D/C: 1147 |
| Convection Solder Reflow ^{*1} | 3X – 0/281 | 0/281 | 0/281 |
| Biased HAST ^{*2} | 264 hours – 0/45 | 0/45 | 0/45 |
| Temperature Cycle ^{*2} | 1000 cycles – 0/77 | 0/77 | 0/77 |
| High Temperature Storage ^{*2} | 1000 hours – 0/77 | 0/77 | 0/77 |
| Wire Bond Pull Strength (gm-f) Avg, StdDev, Max, Min, Cpk | 0/200 Wires 8.09, 1.02, 11.90, 6.45, <u>1.66</u> | 0/200 Wires 7.92, 0.81, 10.20, 6.30, <u>2.02</u> | 0/200, 0/200 Wires 7.00, 0.80, 10.20, 5.55, <u>1.68</u> 7.2, 0.9, 9.8, 4.3, <u>1.6</u> |
| Wire Bond Ball Shear ^{*3} | 0/24 Wires | 0/24 Wires | 0/24 Wires |
| Bond Crater ^{*2} | 0/10 | 0/10 | 0/5 |

Note: *1. Level 3 soak (30°C/60%R.H. for 192 hrs) is used as preconditioning.
*2. Convection solder reflow at 260°C Tp is used as preconditioning.
*3. Performed by Assembly Site.